MOTOROL (2)18供应商 SEMICONDUCTOR TECHNICAL DATA

捷多邦,专业PCB打样工厂

by MJL16218/D

Designer's™ Data Sheet **SCANSWITCH**TM **NPN** Bipolar Power Deflection Transistor For High and Very High Resolution Monitors

The MJL16218 is a state-of-the-art SWITCHMODE™ bipolar power transistor. It is specifically designed for use in horizontal deflection circuits for 20 mm diameter neck, high and very high resolution, full page, monochrome monitors.

- 1500 Volt Collector-Emitter Breakdown Capability
- Typical Dynamic Desaturation Specified (New Turn-Off Characteristic)
- Application Specific State-of-the-Art Die Design

Fast Switching: •

175 ns Inductive Fall Time (Typ)

2000 ns Inductive Storage Time (Typ)

Low Saturation Voltage:

0.2 Volts at 5.0 Amps Collector Current and 2.0 A Base Drive

- Low Collector–Emitter Leakage Current 250 μA Max at 1500 Volts VCES
- High Emitter–Base Breakdown Capability For High Voltage Off Drive Circuits -8.0 Volts (Min)



*Motorola Preferred Device

POWER TRANSISTOR **15 AMPERES** 1500 VOLTS - VCFS **170 WATTS**



TO-3PBL

MAXIMUM RATINGS

Rating	Symbol	Value	Unit Vdc	
Collector–Emitter Breakdown Voltage	VCES	1500		
Collector-Emitter Sustaining Voltage	V _{CEO(sus)}	650	Vdc	
Emitter–Base Voltage	V _{EBO}	8.0	Vdc	
Collector Current — Continuous — Pulsed (1)	IC ICM	15 20	Adc	
Base Current — Continuous — Pulsed (1)	IB IBM	7.0 14	Adc	
Maximum Repetitive Emitter–Base Avalanche Energy	W (BER)	0.2	mJ	
Total Power Dissipation @ $T_C = 25^{\circ}C$ @ $T_C = 100^{\circ}C$ Derated above $T_C = 25^{\circ}C$	PD	170 39 1.49	Watts W/°C	
Operating and Storage Temperature Range	T _J , T _{stg}	– 55 to 125	°C	

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance — Junction to Case	R _{0JC}	0.67	°C/W
Lead Temperature for Soldering Purposes 1/8" from the case for 5 seconds	TL	275	°C

(1) Pulse Test: Pulse Width = 5.0 ms, Duty Cycle \leq 10%.

(2) Proper strike and creepage distance must be provided. WWW.DZSC.COM

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Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented. SOA Limit wes - representing boundaries on device characteristics - are given to facilitate "worst case" design.

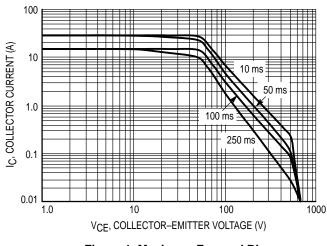
Preferred devices are Motorola recommended choices for future use and best overall value. f.dzsc.com

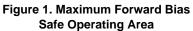


ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS (2)					
Collector Cutoff Current ($V_{CE} = 1500 \text{ V}, V_{BE} = 0 \text{ V}$) ($V_{CE} = 1200 \text{ V}, V_{BE} = 0 \text{ V}$)	ICES	—		250 25	μAdc
Emitter–Base Leakage (V _{EB} = 8.0 Vdc, I _C = 0)	IEBO	_	—	25	μAdc
Emitter–Base Breakdown Voltage (I _E = 1.0 mA, I _C = 0)	V(BR)EBO	8.0	11	—	Vdc
Collector–Emitter Sustaining Voltage (Table 1) ($I_C = 10 \text{ mAdc}, I_B = 0$)	V _{CEO(sus)}	650	—	—	Vdc
ON CHARACTERISTICS (2)					
Collector–Emitter Saturation Voltage (I _C = 5.0 Adc, I _B = 2.0 Adc) (I _C = 3.0 Adc, I _B = 0.6 Adc)	V _{CE(sat)}	_	0.17 0.14	1.0 0.5	Vdc
Base–Emitter Saturation Voltage $(I_C = 5.0 \text{ Adc}, I_B = 1.0 \text{ Adc})$	V _{BE(sat)}	_	0.9	1.5	Vdc
DC Current Gain (I _C = 1.0 A, V _{CE} = 5.0 Vdc) (I _C = 12 A, V _{CE} = 5.0 Vdc)	hFE	— 4.0	24 6.0	-	—
DYNAMIC CHARACTERISTICS					
Dynamic Desaturation Interval (I _C = 5.5 A, I _{B1} = 2.2 A, LB = 1.5 μ H)	t _{ds}	_	350	_	ns
Output Capacitance (V _{CE} = 10 Vdc, I _E = 0, f _{test} = 100 kHz)	C _{ob}	—	300	500	pF
Gain Bandwidth Product (V_{CE} = 10 Vdc, I _C = 0.5 A, f _{test} = 1.0 MHz)	fT	_	0.8	—	MHz
SWITCHING CHARACTERISTICS					
Inductive Load (I _C = 6.0 A, I _B = 2.0 A), High Resolution Deflection Simulator Circuit Table 2 Storage	t _{sv}	_	2000	3000	ns
Fall Time	t _{fi}	—	175	250	

(2) Pulse Test: Pulse Width = 300 μ s, Duty Cycle \leq 2.0%.





SAFE OPERATING AREA

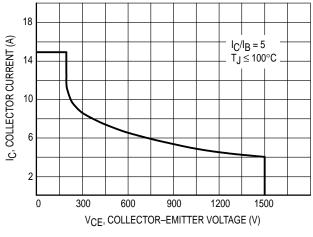


Figure 2. Maximum Reverse Bias Safe Operating Area

SAFE OPERATING AREA (continued)

FORWARD BIAS

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate $I_C - V_{CE}$ limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 1 is based on $T_C = 25^{\circ}C$; $T_{J(pk)}$ is variable depending on power level. Second breakdown pulse limits are valid for duty cycles to 10% but must be derated when $T_C \ge 25^{\circ}C$. Second breakdown limitations do not derate the same as thermal limitations. Allowable current at the voltages shown on Figure 1 may be found at any case temperature by using the appropriate curve on Figure 3.

At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

REVERSE BIAS

For inductive loads, high voltage and high current must be sustained simultaneously during turn–off, in most cases, with the base–to–emitter junction reverse biased. Under these conditions the collector voltage must be held to a safe level at or below a specific value of collector current. This can be accomplished by several means such as active clamping, RC snubbing, load line shaping, etc.

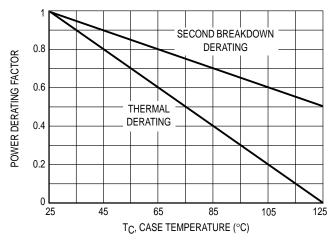
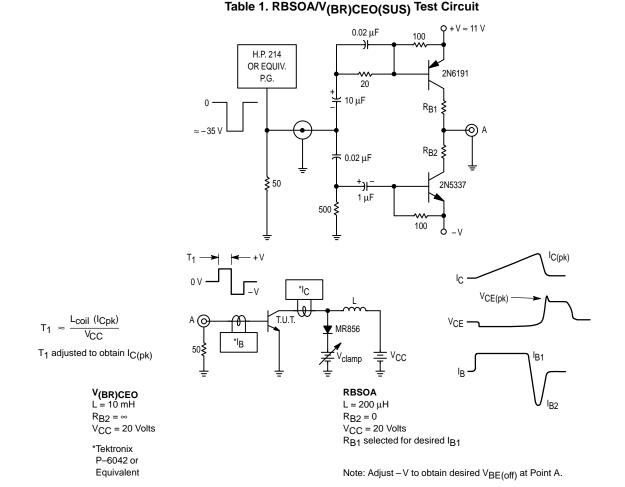
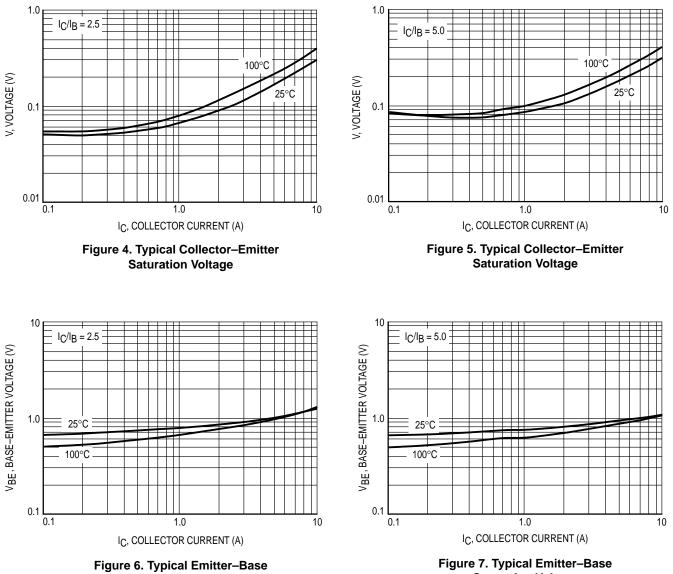


Figure 3. Power Derating

The safe level for these devices is specified as Reverse Biased Safe Operating Area and represents the voltage– current condition allowable during reverse biased turnoff. This rating is verified under clamped conditions so that the device is never subjected to an avalanche mode. Figure 2 gives the RBSOA characteristics.



TYPICAL ELECTRICAL CHARACTERISTICS



Saturation Voltage

Saturation Voltage

TYPICAL ELECTRICAL CHARACTERISTICS (continued)

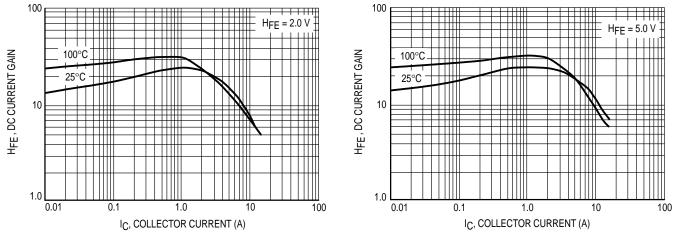


Figure 8. DC Current Gain

Figure 9. DC Current Gain

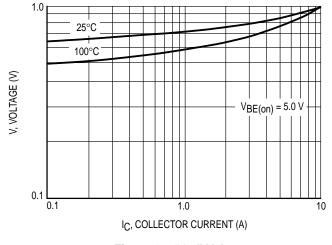


Figure 10. "On" Voltages

DYNAMIC DESATURATION

The SCANSWITCH series of bipolar power transistors are specifically designed to meet the unique requirements of horizontal deflection circuits in computer monitor applications. Historically, deflection transistor design was focused on minimizing collector current fall time. While fall time is a valid figure of merit, a more important indicator of circuit performance as scan rates are increased is a new characteristic, "dynamic desaturation." In order to assure a linear collector current ramp, the output transistor must remain in hard saturation during storage time and exhibit a rapid turn-off transition. A sluggish transition results in serious consequences. As the saturation voltage of the output transistor increases, the voltage across the yoke drops. Roll off in the collector current ramp results in improper beam deflection and distortion of the image at the right edge of the screen. Design changes have been made in the structure of the SCAN-SWITCH series of devices which minimize the dynamic desaturation interval. Dynamic desaturation has been defined in terms of the time required for the V_{CE} to rise from 1.0 to 5.0 volts (Figures 9 and 10) and typical performance at optimized drive conditions has been specified. Optimization of device structure results in a linear collector current ramp, excellent turn-off switching performance, and significantly lower overall power dissipation.

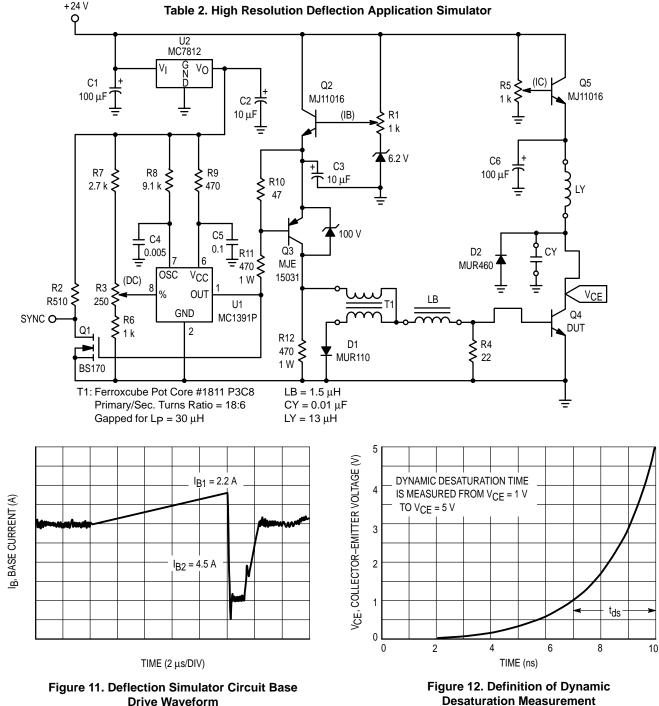
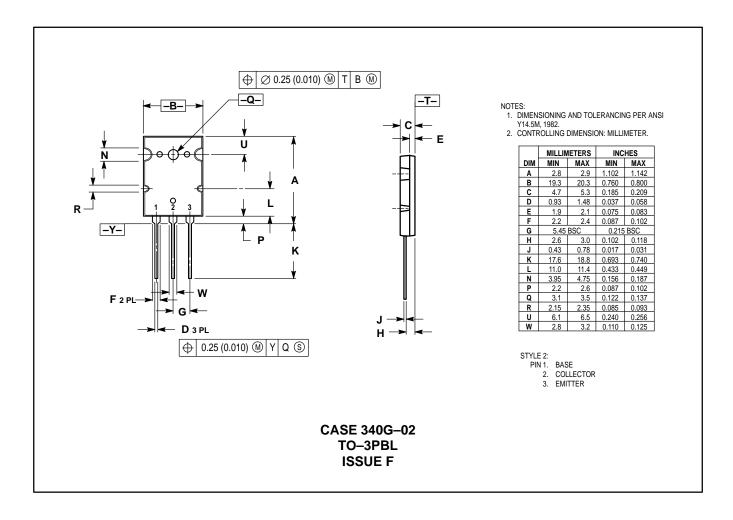


Table 2. High Resolution Deflection Application Simulator

PACKAGE DIMENSIONS



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